

Notice of References Cited	Application/Control No. 10/509,867	Applicant(s)/Patent Under Reexamination TAKANO ET AL.	
	Examiner Christopher M. Brandt	Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0009061 A1	01-2002	Willenegger, Serge	370/328
*	B	US-6,351,650 B1	02-2002	Lundby et al.	455/522
*	C	US-2002/0077140 A1	06-2002	Monogioudis et al.	455/522
*	D	US-6,473,624 B1	10-2002	Corbett et al.	455/522
*	E	US-2002/0173309 A1	11-2002	Shahidi et al.	455/442
*	F	US-2003/0021243 A1	01-2003	Hamalainen, Seppo	370/329
*	G	US-6,546,252 B1	04-2003	Jetzek et al.	455/437
*	H	US-2003/0157953 A1	08-2003	Das et al.	455/522
*	I	US-6,823,193 B1	11-2004	Persson et al.	455/522
*	J	US-6,983,165 B1	01-2006	Hiramatsu, Katsuhiko	455/522
*	K	US-7,010,318 B2	03-2006	Chang et al.	455/522
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.